

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	35	("local probe storage array" OR "probe storage" OR "probe storage array").clm.	US-PGPUB	OR	OFF	2006/02/20 15:23
S1	15	local NEAR3 probe NEAR3 storage NEAR3 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 10:49
S2	2	("20040019757").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 15:05
S3	13	local NEAR2 probe NEAR2 storage NEAR2 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 15:20
S4	4	local NEAR1 probe NEAR1 storage NEAR1 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 10:50
S6	4749645	(INTERNATIONAL BUSINESS MACHINES CORP\$.as.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 11:43
S7	553	(711/104).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 11:55
S8	13	local NEAR2 probe NEAR2 storage NEAR2 array	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 15:21
S9	28	(local NEAR2 probe NEAR2 storage NEAR2 array) OR (local NEAR2 probe NEAR2 array)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/22 15:22
S10	26896	"711"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:36
S11	661916	367/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 08:56

S12	2759	S10 AND S11	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 08:56
S14	686053	S10 OR S11	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 09:04
S15	28	(local NEAR2 probe NEAR2 storage NEAR2 array) OR (local NEAR2 probe NEAR2 array)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 09:04
S16	13	S14 AND S15	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 15:06
S18	51	"processing elements" NEAR4 (sensor OR probe)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:37
S19	0	S12 AND S18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:37
S20	0	S14 AND S18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:37
S21	185	"processing elements" WITH (sensor OR probe)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:39
S22	5	S21 AND S14	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/26 11:40
S23	1	("5307311").PN.	USPAT; USOCR	OR	OFF	2005/09/26 15:06
S24	563761	"data processing element" NEAR "5" ("RAM" OR "random access memory")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 15:06

S25	21	"data processing element" NEAR5 ("RAM" OR "random access memory")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:12
S26	81	dedicated WITH ("user data" AND ("program code" OR "code"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:14
S27	21	dedicated WITH ("user data" NEAR5("program code" OR "code"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 08:48
S28	3156	"storage surface"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:15
S29	2	S28 AND S26	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:16
S30	143	"storage surface" WITH ("user data" AND ("program code" OR "code"))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:20
S31	2	dedicated WITH ("storage surface" WITH ("user data" AND ("program code" OR "code")))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/27 16:21
S32	707	((711/4) or (711/123)).CCLS.	USPAT; USOCR	OR	OFF	2005/09/28 09:27
S33	3156	"storage surface"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 08:49
S34	10	S32 AND S33	US-PGPUB; USPAT	OR	OFF	2005/09/28 08:53
S35	8	S32 AND "processing elements"	US-PGPUB; USPAT	OR	OFF	2005/09/28 08:53
S36	1902	((711/4) or (711/123) or (711/129) or (711/173)).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 09:28

S37	20	S36 AND S33	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/28 09:29
S38	4892	"storage array"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/18 13:01
S39	3259	"storage surface"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/18 13:01
S40	31	S38 AND S39	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/02/18 13:01


[Search Result - Print Format](#)
[< Back](#)

Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, II CNF = IEE Conference, IEEE STD = IEEE Standard

1. **Signal processing for probe storage**
 Pozidis, H.; Bachtold, P.; Cherubini, G.; Eleftheriou, E.; Hagleitner, C.; Pantazi, A.; Sebastian, A.;
 Acoustics, Speech, and Signal Processing, 2005. Proceedings. (ICASSP '05). IEEE International Conference on
 Volume 5, 18-23 March 2005 Page(s):v/745 - v/748 Vol. 5
 IEEE CNF
2. **Servo and tracking algorithm for a probe storage system**
 Dong-Ki Min; Seungbum Hong;
 Magnetics, IEEE Transactions on
 Volume 41, Issue 2, Feb. 2005 Page(s):855 - 859
 IEEE JNL
3. **Two-sensor-based H_∞ control for nanopositioning in probe storage**
 Pantazi, A.; Sebastian, A.; Pozidis, H.; Eleftheriou, E.;
 Decision and Control, 2005 and 2005 European Control Conference. CDC-ECC '05. 44th IEEE Conference on
 12-15 Dec. 2005 Page(s):1174 - 1179
 IEEE CNF
4. **Nanopositioning for probe storage**
 Sebastian, A.; Pantazi, A.; Cherubini, G.; Eleftheriou, E.; Lantz, M.A.; Pozidis, H.;
 American Control Conference, 2005. Proceedings of the 2005
 8-10 June 2005 Page(s):4181 - 4186 vol. 6
 IEEE CNF
5. **Analytical and micromagnetic-based modeling of quantization noise in MFM-based pulse-width-Modulation perpendicular recording**
 El-Sayed, R.T.; Carley, L.R.;
 Magnetics, IEEE Transactions on
 Volume 40, Issue 4, July 2004 Page(s):2326 - 2328
 IEEE JNL
6. **The race to the bottom [consumer nanodevice]**
 Goldstein, H.;
 Spectrum, IEEE
 Volume 42, Issue 3, March 2005 Page(s):32 - 39
 IEEE JNL
7. **Fabrication of patterned Pt/Co multilayers for high-density probe storage**
 Nutter, P.W.; Du, H.; Vorithitikul, V.; Edmundson, D.; Hill, E.W.; Miles, J.J.; Wright, C.D.;
 Science, Measurement and Technology, IEE Proceedings-
 Volume 150, Issue 5, 3 Sept. 2003 Page(s):227 - 231
 IEE JNL
8. **Future read channel technologies and challenges for high density data storage applications**
 Kurtas, E.M.; Erden, M.F.; Yang, X.;
 Acoustics, Speech, and Signal Processing, 2005. Proceedings. (ICASSP '05). IEEE International Conference on
 Volume 5, 18-23 March 2005 Page(s):v/737 - v/740 Vol. 5
 IEEE CNF

9. **On the retention time distribution of dual-channel vertical DRAM technologies**
Beintner, J.; Li, Y.; Casarotto, D.; Chidambarrao, D.; McStay, K.; Wang, G.; Hummler, K.; Divakaruni, R.; Bergner, A.; Crabbe, E.; Mueller, W.; Poechmueller, P.; Bronner, G.;
VLSI Technology, Systems, and Applications, 2003 International Symposium on
2003 Page(s):243 - 246
IEEE CNF
10. **Terabit-per-square-inch data storage using phase-change media and scanning electrical nanoprobe**
Wright, C.D.; Armand, M.; Aziz, M.M.;
Nanotechnology, IEEE Transactions on
Volume 5, Issue 1, Jan. 2006 Page(s):50 - 61
IEEE JNL
11. **Performance analysis of a 0.3-Tb/in²/ low-power MFM-based scanning-probe device**
El-Sayed, R.T.; Carley, L.R.;
Magnetism, IEEE Transactions on
Volume 39, Issue 6, Nov. 2003 Page(s):3566 - 3574
IEEE JNL
12. **Demonstration of thermomechanical recording at 641 Gbit/in²**
Pozidis, H.; Haberle, W.; Wiesmann, D.; Drechsler, U.; Despont, M.; Albrecht, T.R.; Eleftheriou, E.;
Magnetism, IEEE Transactions on
Volume 40, Issue 4, July 2004 Page(s):2531 - 2536
IEEE JNL
13. **Media and tip trajectory optimization for high-density MFM-based perpendicular recording**
El-Sayed, R.T.; Carley, L.R.;
Magnetism, IEEE Transactions on
Volume 41, Issue 3, March 2005 Page(s):1209 - 1217
IEEE JNL
14. **Servo and tracking algorithm for a probe storage system**
Dong-Ki Min; Seungbum Hong;
Asia-Pacific Magnetic Recording Conference, 2004. APMRC 2004
16-19 Aug. 2004 Page(s):70 - 71
IEEE CNF
15. **Thousands of microcantilevers for highly parallel and ultra-dense data storage**
Vettiger, P.; Albrecht, T.; Despont, M.; Drechsler, U.; Durig, U.; Gotsmann, B.; Jubin, D.; Haberle, W.; Lantz, M.A.;
Rothuizen, H.; Stutz, R.; Wiesmann, D.; Binnig, G.K.; Bachtold, P.; Cherubini, G.; Hagleitner, C.; Loeliger, T.; Panta
A.; Pozidis, H.; Eleftheriou, E.;
Electron Devices Meeting, 2003. IEDM '03 Technical Digest. IEEE International
8-10 Dec. 2003 Page(s):32.1.1 - 32.1.4
IEEE CNF



□ Search Result - Print Format

[< Back](#)

Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, II CNF = IEE Conference, IEEE STD = IEEE Standard

1. **Design of atomic force microscope cantilevers for combined thermomechanical writing and thermal reading in array operation**
King, W.P.; Kenny, T.W.; Goodson, K.E.; Cross, G.L.W.; Despont, M.; Durig, U.T.; Rothuizen, H.; Binnig, G.; Vettiger, P.;
Microelectromechanical Systems, Journal of
Volume 11, Issue 6, Dec. 2002 Page(s):765 - 774
IEEE JNL
2. **The "millipede" - nanotechnology entering data storage**
Vettiger, P.; Cross, G.; Despont, M.; Drechsler, U.; Durig, U.; Gotsmann, B.; Haberle, W.; Lantz, M.A.; Rothuizen, H.E.; Stutz, R.; Binnig, G.K.;
Nanotechnology, IEEE Transactions on
Volume 1, Issue 1, March 2002 Page(s):39 - 55
IEEE JNL
3. **Millipede - a MEMS-based scanning-probe data-storage system**
Eleftheriou, E.; Antonakopoulos, T.; Binnig, G.K.; Cherubini, G.; Despont, M.; Dholakia, A.; Durig, U.; Lantz, M.A.; Pozidis, H.; Rothuizen, H.E.; Vettiger, P.;
Magnetics, IEEE Transactions on
Volume 39, Issue 2, Mar 2003 Page(s):938 - 945
IEEE JNL
4. **A beautiful noise [invention of STM and AFM]**
Goldstein, H.;
Spectrum, IEEE
Volume 41, Issue 5, May 2004 Page(s):50 - 52
IEEE JNL
5. **CMOS sensor array with cell-level analog-to-digital conversion for local probe data storage**
Loeliger, T.; Bachtold, P.; Binnig, G.K.; Cherubini, G.; Durig, U.; Eleftheriou, E.; Vettiger, P.; Uster, M.; Jackel, H.;
Solid-State Circuits Conference, 2002. ESSCIRC 2002. Proceedings of the 28th European
24-26 Sept. 2002 Page(s):623 - 626
IEEE CNF
6. **The millipede, a very dense, highly parallel scanning-probe data-storage system**
Cherubini, G.; Antonakopoulos, T.; Bachtold, P.; Binnig, G.K.; Despont, M.; Drechsler, U.; Dholakia, A.; Durig, U.; Eleftheriou, E.; Gotsmann, B.; Haberle, W.; Lantz, M.A.; Loeliger, T.; Pozidis, H.; Rothuizen, H.E.; Stutz, R.; Vettiger, P.;
Solid-State Circuits Conference, 2002. ESSCIRC 2002. Proceedings of the 28th European
24-26 Sept. 2002 Page(s):121 - 125
IEEE CNF
7. **A highly parallel probe-based storage system**
Despont, M.; Altbauer, T.; Bachtold, P.; Binnig, G.K.; Cherubini, G.; Drechsler, U.; Durig, U.; Eleftheriou, E.; Gotsmann, B.; Haberle, W.; Hagleitner, C.; Jubin, D.; Knoll, A.; Lantz, M.A.; Pantazi, A.; Pozidis, H.; Rothuizen, H.; Sebastian, A.; Stutz, R.; Vettiger, P.; Wiemann, D.; Windeln, J.;
Microprocesses and Nanotechnology Conference, 2004. Digest of Papers. 2004 International
Oct. 27-29, 2004 Page(s):4 - 5
IEEE CNF

8. **Thousands of microcantilevers for highly parallel and ultra-dense data storage**
Vettiger, P.; Albrecht, T.; Despont, M.; Drechsler, U.; Durig, U.; Gotsmann, B.; Jubin, D.; Haberle, W.; Lantz, M.A.; Rothuizen, H.; Stutz, R.; Wiesmann, D.; Binnig, G.K.; Bachtold, P.; Cherubini, G.; Hagleitner, C.; Loeliger, T.; Panta A.; Pozidis, H.; Eleftheriou, E.;
Electron Devices Meeting, 2003. IEDM '03 Technical Digest. IEEE International
8-10 Dec. 2003 Page(s):32.1.1 - 32.1.4
IEEE CNF
9. **"Millipede": a MEMS-based scanning-probe data-storage system**
Eleftheriou, E.; Antonakopoulos, T.; Binnig, G.K.; Cherubini, G.; Despont, M.; Dholakia, A.; Durig, U.; Lantz, M.A.; Pozidis, H.; Rothuizen, H.; Vettiger, P.;
Magnetic Recording Conference, 2002. Digest of the Asia-Pacific
27-29 Aug. 2002 Page(s):CE2-01 - CE2-02
IEEE CNF
10. **Integrated microheaters for in-situ flying-height control of sliders used in hard-disk drives**
Machtle, P.; Berger, R.; Dietzel, A.; Despont, M.; Haberle, W.; Stutz, R.; Binnig, G.K.; Vettiger, P.;
Micro Electro Mechanical Systems, 2001. MEMS 2001. The 14th IEEE International Conference on
21-25 Jan 2001 Page(s):196 - 199
IEEE CNF
11. **Millipede-a highly-parallel dense scanning-probe-based data-storage system**
Lutwyche, M.I.; Cross, G.; Despont, M.; Drechsler, U.; Durig, U.; Haberle, W.; Rothuizen, H.; Stutz, R.; Widmer, R.; Binnig, G.K.; Vettiger, P.;
Solid-State Circuits Conference, 2000. Digest of Technical Papers. ISSCC. 2000 IEEE International
7-9 Feb. 2000 Page(s):126 - 127, 450
IEEE CNF
12. **The "Millipede"-more than one thousand tips for parallel and dense AFM data storage**
Vettiger, P.; Gross, G.; Despont, M.; Drechsler, U.; During, U.; Haberle, W.; King, W.P.; Lutwyche, M.I.; Rothuizen, H.; Stutz, R.; Widmer, R.; Binnig, G.K.;
Asia-Pacific Magnetic Recording Conference, 2000. APMRC 2000
6-8 Nov. 2000 Page(s):MC1/1 - MC1/2
IEEE CNF
13. **Dual-cantilever AFM probe for combining fast and coarse imaging with high-resolution imaging**
Despont, M.; Takahashi, H.; Ichihara, S.; Shirakawabe, Y.; Shimizu, N.; Inoue, A.; Haberle, W.; Binnig, G.K.; Vettiger, P.;
Micro Electro Mechanical Systems, 2000. MEMS 2000. The Thirteenth Annual International Conference on
23-27 Jan. 2000 Page(s):126 - 131
IEEE CNF
14. **VLSI-NEMS chip for AFM data storage**
Despont, M.; Brugger, J.; Drechsler, U.; Durig, U.; Haberle, W.; Lutwyche, M.; Rothuizen, H.; Stutz, R.; Widmer, R.; Rohrer, H.; Binnig, G.; Vettiger, P.;
Micro Electro Mechanical Systems, 1999. MEMS '99. Twelfth IEEE International Conference on
17-21 Jan. 1999 Page(s):564 - 569
IEEE CNF
15. **Microfabrication and parallel operation of 5x5 2D AFM cantilever arrays for data storage and imaging**
Lutwyche, M.; Andreoli, C.; Binnig, G.; Brugger, J.; Drechsler, U.; Haeberle, W.; Rohrer, H.; Rothuizen, H.; Vettiger, P.;
Micro Electro Mechanical Systems, 1998. MEMS 98. Proceedings., The Eleventh Annual International Workshop on
25-29 Jan. 1998 Page(s):8 - 11
IEEE CNF
16. **Scanning probe microscopy-how does it work and what might you use it for?**

Leckenby, J.;
New Microscopies in Medicine and Biology, IEE Colloquium on
1994 Page(s):1 - 3
IEE CNF



© Copyright 2006 IEEE -